



IECQ QUALITY ASSESSMENT SYSTEM (IECQ)

For rules and details of the IECQ visit www.iecq.org

IECQ Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.:	IECQ-L DEKRA 16.0002-04	Issue No.:	1	Status:	Current
Additional Site to Certification: IECQ-L DEKRA 16.0002		Originally Issued: 2016/08/17			
Supersedes:		Issue Date:	2025/08/14	Site Added:	2025/08/14
CB Reference No.:	DEKRA-T5E-003	Expiration:	2028/08/16		

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The organization, facilities and procedures have been assessed by the IECQ Certification Body in accordance with IECQ 03-1 and IECQ 03-6 for issuance of this certificate and found to be in conformity with the applicable requirements of the IECQ Independent Testing Laboratory Assessment Program Requirements Scheme and in respect of ISO/IEC 17025:2017 for the testing of component product under the IECQ.

Scope:

Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

See attached Schedule of Scope

-- Attached Schedule: IECQ-L DEKRA 16.0002-04-S.pdf --

Approved by Certification Body (CB): DEKRA Certification B.V.

Meander 1051
Arnhem
Netherlands

Authorized person:
Ted Gaertner



The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.

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Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L DEKRA 16.0002-04

CB Certificate No.: DEKRA-T5E-003

Schedule Number: IECQ-L DEKRA 16.0002-04-S Rev No.: 1 Revision Date: 2025/08/14 Page 1 of 1

Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

Description test	Standard
TEM analysis	A00-530-30057, A00-530-30197
DUAL BEAM FIB analysis	A00-530-30130

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